



Description

The SQD100N02_3M5L4GE3 uses advanced trench technology to provide excellent RDS(ON), low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.



TO252-2L

General Features

V_{DS} = 20V I_D =80 A

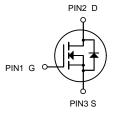
 $R_{DS(ON)} < 5m\Omega$ @ $V_{GS}=4.5V$

Application

Battery protection

Load switch

Uninterruptible power supply



N-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
SQD100N02_3M5L4GE3	TO252-2L	HXY MOSFET	2500

Absolute Maximum Ratings(T_C=25°C unless otherwise noted)

Symbol	Parameter	Limit	Unit
V _{DS}	Drain-Source Voltage	20	V
V _G s	Gate-Source Voltage	±12	V
I _D	Drain Current-Continuous	80	Α
I _D (100°C)	Drain Current-Continuous(Tc=100°C)	42	А
Ірм	Pulsed Drain Current	210	А
P _D	Maximum Power Dissipation	70	W
	Derating factor	0.48	W/°C
Eas	Single pulse avalanche energy (Note 5)	200	mJ
TJ,Tstg	Operating Junction and Storage Temperature Range	-55 To 150	°C



SQD100N02_3M5L4GE3

N-Channel Enhancement Mode MOSFET

Thermal Characteristic

Thermal Resistance, Junction-to-Case ^(Note 2)	R _{θJC}	2.1	°C/W	
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Electrical Characteristics (T_C=25°C unless otherwise noted)

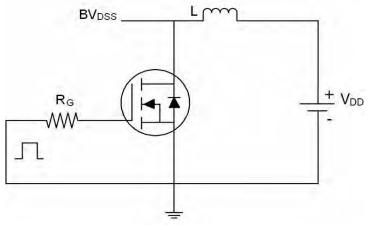
Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics				,		
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	20	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =20V,V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±12V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} ,I _D =250µA	0.5	0.75	1.0	V
Drain Sauras On State Registance	В	V _{GS} =4.5V, I _D =20 A	-	3.5	5	mΩ
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =2.5V, I _D =15A		5.5	7	mΩ
Forward Transconductance	g Fs	V _{DS} =10V,I _D =20A	15	-	-	S
Dynamic Characteristics (Note4)	·					
Input Capacitance	C _{lss}	\/ -40\/\/ -0\/	-	2000	-	PF
Output Capacitance	Coss	V _{DS} =10V,V _{GS} =0V,	-	500	-	PF
Reverse Transfer Capacitance	C _{rss}	F=1.0MHz	-	200	-	PF
Switching Characteristics (Note 4)				•		
Turn-on Delay Time	t _{d(on)}		-	6.4	-	nS
Turn-on Rise Time	t _r	V_{DD} =10V, I_D =2A, R_L =1 Ω	-	17.2	-	nS
Turn-Off Delay Time	t _{d(off)}	V_{GS} =4.5 V , R_{G} =3 Ω	-	29.6	-	nS
Turn-Off Fall Time	t _f		-	16.8	-	nS
Total Gate Charge	Qg)/ 40\/ L 00A	-	27		nC
Gate-Source Charge	Q _{gs}	V _{DS} =10V,I _D =20A,	-	6.5		nC
Gate-Drain Charge	Q _{gd}	V _{GS} =10V	-	6.4		nC
Drain-Source Diode Characteristics						
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =10A	-		1.2	V
Diode Forward Current (Note 2)	Is		-	-	80	Α
Reverse Recovery Time	t _{rr}	TJ = 25°C, IF = 20A	-	25	-	nS
Reverse Recovery Charge	Qrr	di/dt = 100A/µs ^(Note3)	-	24	-	nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

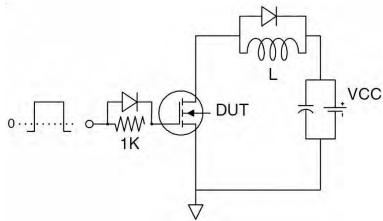
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board, $t \le 10$ sec.
- **3.** Pulse Test: Pulse Width ≤ 300μ s, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production
- $\textbf{5.} \ E_{AS} \ condition: Tj=25^{\circ}C, V_{DD}=10V, V_{G}=10V, L=0.5mH, Rg=25\Omega,$

Test circuit

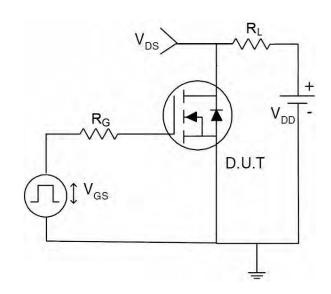
1) E_{AS} Test Circuit



2) Gate Charge Test Circuit



3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics (Curves)

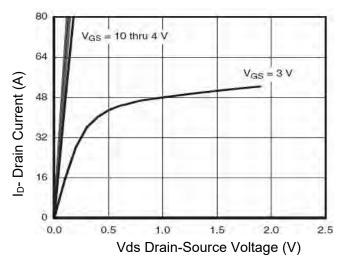
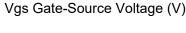


Fig.1 Typical Output Characteristics



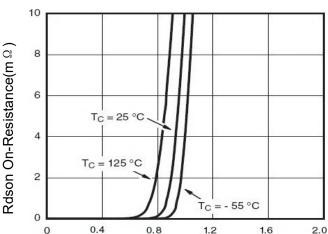


Figure 2 Transfer Characteristics

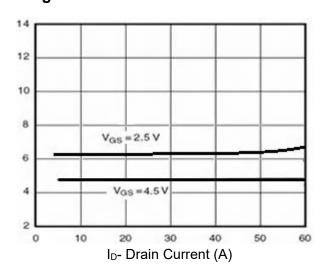


Figure 3 Rdson- Drain Current

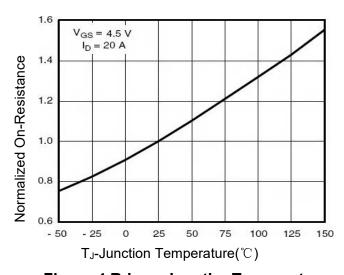


Figure 4 Rdson-JunctionTemperature

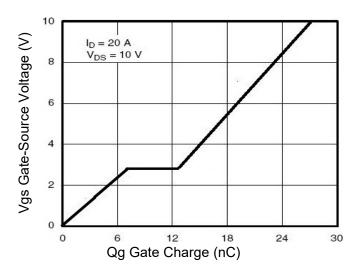


Figure 5 Gate Charge

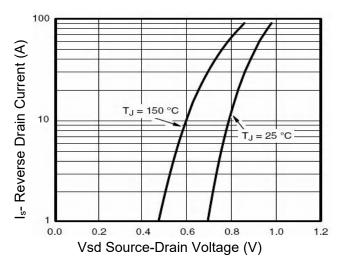


Figure 6 Source- Drain Diode Forward

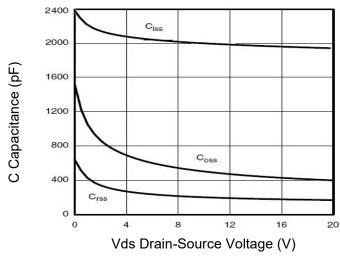


Figure 7 Capacitance vs Vds

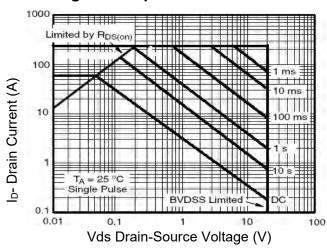


Figure 8 Safe Operation Area

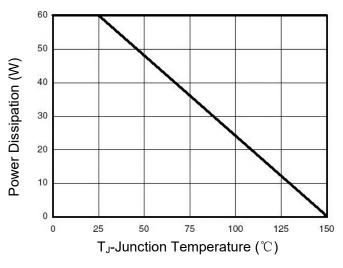


Figure 9 Power De-rating

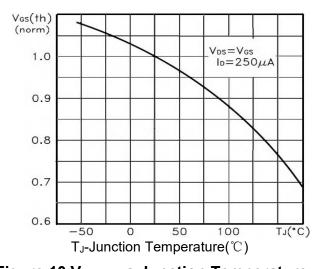
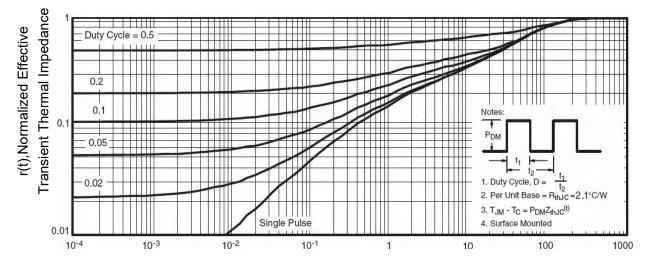


Figure 10 V_{GS(th)} vs Junction Temperature

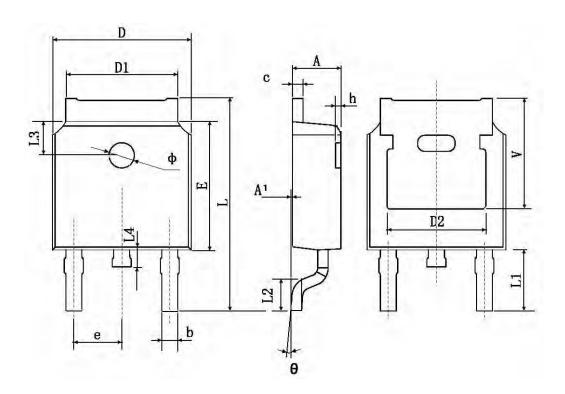


Square Wave Pluse Duration(sec)

Figure 11 Normalized Maximum Transient Thermal Impedance

N-Channel Enhancement Mode MOSFET

TO252-2L Package Information



Complete	Dimensions	In Millimeters	Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
А	2.200	2.400	0.087	0.094	
A1	0.000	0.127	0.000	0.005	
b	0.660	0.860	0.026	0.034	
С	0.460	0.580	0.018	0.023	
D	6.500	6.700	0.256	0.264	
D1	5.100	5.460	0.201	0.215	
D2	0.483 TYP.		0.190	TYP.	
Е	6.000	6.200	0.236	0.244	
е	2.186	2.386	0.086	0.094	
L	9.800	10.400	0.386	0.409	
L1	2.900 TYP.		0.114 TYP.		
L2	1.400	1.700	0.055	0.067	
L3	1.600 TYP.		0.063 TYP.		
L4	0.600	1.000	0.024	0.039	
Ф	1.100	1.300	0.043	0.051	
θ	0°	8°	0°	8°	
h	0.000	0.300	0.000	0.012	
V	5.350 TYP.		0.211 TYP.		

SQD100N02 3M5L4GE3

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